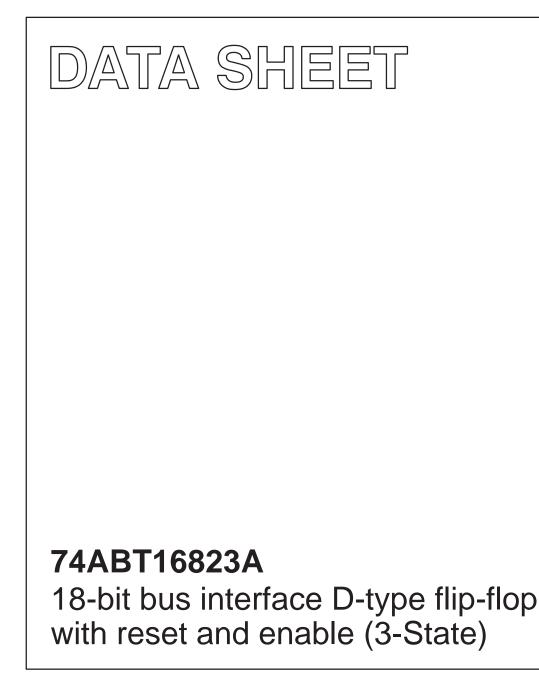
INTEGRATED CIRCUITS



Product data Replaces data sheet 74ABT16823A/ABTH16823A of 1998 Feb 27 2004 Feb 02



74ABT16823A

FEATURES

- Two sets of high speed parallel registers with positive edge-triggered D-type flip-flops
- Ideal where high speed, light loading, or increased fan-in are required with MOS microprocessors
- Live insertion/extraction permitted
- Power-up 3-State
- Power-up Reset
- Output capability: +64 mA/-32 mA

QUICK REFERENCE DATA

- Latch-up protection exceeds 500 mA per Jedec Std 17
- ESD protection exceeds 2000 V per MIL STD 883 Method 3015 and 200 V per Machine Model

DESCRIPTION

The 74ABT16823A 18-bit bus interface register is designed to eliminate the extra packages required to buffer existing registers and provide extra data width for wider data/address paths of buses carrying parity.

The 74ABT16823A has two 9-bit wide buffered registers with Clock Enable ($\overline{\text{NE}}$) and Master Reset ($\overline{\text{NR}}$) which are ideal for parity bus interfacing in high microprogrammed systems.

The registers are fully edge-triggered. The state of each D input, one set-up time before the LOW-to-HIGH clock transition is transferred to the corresponding flip-flop's Q output.

SYMBOL	PARAMETER	CONDITIONS T _{amb} = 25 °C; GND = 0 V	TYPICAL	UNIT
t _{PLH} t _{PHL}	Propagation delay nCP to nQx	C _L = 50 pF; V _{CC} = 5 V	2.3 1.9	ns
C _{IN}	Input capacitance	$V_I = 0 V \text{ or } V_{CC}$	4	pF
C _{OUT}	Output capacitance	$V_O = 0 V \text{ or } V_{CC}$; 3-State	6	pF
I _{CCZ}	Quiescent supply current	Outputs disabled; V_{CC} = 5.5 V	500	μΑ
I _{CCL}	Quotoon supply current	Outputs low; V_{CC} = 5.5 V	9	mA

ORDERING INFORMATION

 $T_{amb} = -40 \circ C \text{ to } +85 \circ C$

Type number	Package	ackage					
	Name	Description	Version				
74ABT16823ADL	SSOP56	plastic shrink small outline package; 56 leads; body width 7.5 mm	SOT371-1				
74ABT16823ADGG	TSSOP56	plastic thin shrink small outline package; 56 leads; body width 6.1 mm	SOT364-1				

PIN DESCRIPTION

PIN NUMBER	SYMBOL	FUNCTION
2, 27	1 0E , 2 0E	Output enable input (active-LOW)
54, 52, 51, 49, 48, 47, 45, 44, 43 42, 41, 40, 38, 37, 36, 34, 33, 31	1D0-1D8 2D0-2D8	Data inputs
3, 5, 6, 8, 9, 10, 12, 13, 14 15, 16, 17, 19, 20, 21, 23, 24, 26	1Q0-1Q8 2Q0-2Q8	Data outputs
56, 29	1CP, 2CP	Clock pulse input (active rising edge)
55, 30	1CE, 2CE	Clock enable input (active-LOW)
1, 28	1 <u>MR</u> , 2 <u>MR</u>	Master reset input (active-LOW)
4, 11, 18, 25, 32, 39, 46, 53	GND	Ground (0 V)
7, 22, 35, 50	V _{CC}	Positive supply voltage

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PIN CONFIGURATION

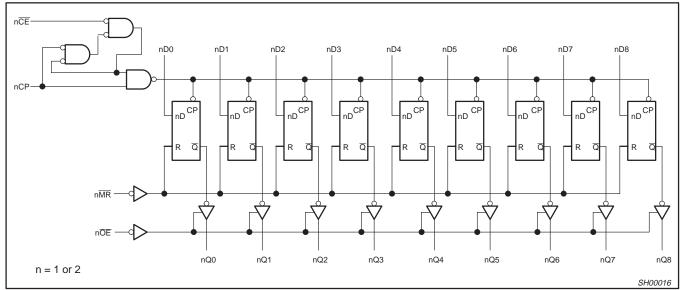
1MR	1		56	1CP
1 0E	2		55	1CE
1Q0	3		54	1D0
GND	4		53	GND
1Q1	5		52	1D1
1Q2	6		51	1D2
V _{CC}	7		50	V _{CC}
1Q3	8		49	1D3
1Q4	9		48	1D4
1Q5	10		47	1D5
GND	11		46	GND
1Q6	12		45	1D6
1Q7	13		44	1D7
1Q8	14		43	1D8
2Q0	15		42	2D0
2Q1	16		41	2D1
2Q2	17		40	2D2
GND	18		39	GND
2Q3	19		38	2D3
2Q4	20		37	2D4
2Q5	21		36	2D5
V _{CC}	22		35	V _{CC}
2Q6	23		34	2D6
2Q7	24		33	2D7
GND	25		32	GND
2Q8	26		31	2D8
2 <u>0</u> E	27		30	2 CE
2MR	28		29	2CP
		SHO	. 0014	

LOGIC SYMBOL (IEEE/IEC)

				1	
10E	2	EN1			
1MR	1	R2			
1CE	55 📐	G3			
1CP	_56	> 3C4			
2OE	27	EN5			
2MR	28	R6			
2CE	30	G7			
2CP	29	> 7C8			
	54			3	
1D0	52	4D	1, 2 ∇	5	1Q0
1D1	51			6	1Q1
1D2	49			8	1Q2
1D3	49	- 			1Q3
1D4		-		9	1Q4
1D5	47			10	1Q5
1D6	<u>45</u> 44			12	1Q6
1D7				13	1Q7
1D8	43			14	1Q8
2D0	42	8D	5,6∇	15	2Q0
2D1	41	-		16	2Q1
2D2	40	-		17	2Q2
2D3	38	-		19	2Q3
2D4	37	-		20	2Q4
2D5	36			21	2Q5
2D6	34	-		23	2Q6
2D7	33			24	2Q7
2D8	_31	-		25	2Q8
				SH	100015

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LOGIC DIAGRAM



FUNCTION TABLE

		INPUTS			OUTPUTS	OPERATING MODE	
nOE	nMR	nCE	nCP	nDx	nQ0 – nQ8		
L	L	Х	Х	Х	L	Clear	
L	Н	L	Ŷ	h	Н	Load and read data	
L	Н	L	Ŷ	I	L		
L	Н	Н	Ŷ	Х	NC	Hold	
Н	Х	Х	Х	Х	Z	High impedance	

H =

High voltage level High voltage level one set-up time prior to the LOW-to-HIGH clock transition h =

L = Low voltage level

Low voltage level one set-up time prior to the LOW-to-HIGH clock transition
 NC= No change

= Don't care

XZ↑↑ High impedance "off" state
 LOW-to-HIGH clock transition

Not a LOW-to-HIGH clock transition =

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ABSOLUTE MAXIMUM RATINGS^{1, 2}

SYMBOL	PARAMETER	CONDITIONS	RATING	UNIT
V _{CC}	DC supply voltage		-0.5 to +7.0	V
I _{IK}	DC input diode current	V ₁ < 0 V	-18	mA
VI	DC input voltage ³		-1.2 to +7.0	V
I _{OK}	DC output diode current	V _O < 0 V	-50	mA
V _{OUT}	DC output voltage ³	output in Off or HIGH state	-0.5 to +5.5	V
		output in LOW state	128	
IOUT	DC output current	output in HIGH state	-64	mA
T _{stg}	Storage temperature range		–65 to 150	°C

NOTES:

 Stresses beyond those listed may cause permanent damage to the device. These are stress ratings only and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

 The performance capability of a high-performance integrated circuit in conjunction with its thermal environment can create junction temperatures which are detrimental to reliability. The maximum junction temperature of this integrated circuit should not exceed 150°C.
 The input and output voltage rating may be exceeded if the input and output current ratings are observed.

3. The input and output voltage ratings may be exceeded if the input and output current ratings are observed.

RECOMMENDED OPERATING CONDITIONS

SYMBOL	PARAMETER	LIM	ITS	UNIT	
STWBOL	FARAMETER	MIN	5.5 V _{CC}	UNIT	
V _{CC}	DC supply voltage	4.5	5.5	V	
VI	Input voltage	0	V _{CC}	V	
V _{IH}	HIGH-level input voltage	2.0	-	V	
V _{IL}	LOW-level input voltage	-	0.8	V	
I _{ОН}	HIGH-level output current	-	-32	mA	
I _{OL}	LOW-level output current	-	64	mA	
Δt/Δv	Input transition rise or fall rate	0	10	ns/V	
T _{amb}	Operating free-air temperature range	-40	+85	°C	

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Product data

DC ELECTRICAL CHARACTERISTICS

					LIMIT	S		
SYMBOL	PARAMETER	TEST CONDITIONS	T _{amb} = +25 °C			T _{amb} = −40 °C to +85 °C		
			MIN	ТҮР	МАХ	MIN	MAX	1
V _{IK}	Input clamp voltage	V _{CC} = 4.5 V; I _{IK} = -18 mA	-	-0.9	-1.2	-	-1.2	V
		V_{CC} = 4.5 V; I_{OH} = -3 mA; V_I = V_{IL} or V_{IH}	2.5	2.9	-	2.5	-	V
V _{OH}	HIGH-level output voltage	V_{CC} = 5.0 V; I_{OH} = –3 mA; V_{I} = V_{IL} or V_{IH}	3.0	3.4	-	3.0	-	V
		V_{CC} = 4.5 V; I_{OH} = -32 mA; V_I = V_{IL} or V_{IH}	2.0	2.4	-	2.0	-	V
V _{OL}	LOW-level output voltage	V_{CC} = 4.5 V; I_{OL} = 64 mA; V_{I} = V_{IL} or V_{IH}	-	0.42	0.55	-	0.55	V
V _{RST}	Power-up output LOW voltage ³	V_{CC} = 5.5 V; I_{OL} = 1 mA; V_{I} = GND or V_{CC}	-	0.13	0.55	-	0.55	V
I _I	Input leakage curent	$V_{CC} = 5.5 \text{ V}; \text{ V}_{I} = V_{CC} \text{ or GND}$	-	±0.01	±1	-	±1	μA
I _{OFF}	Power-off leakage current	V_{CC} = 0.0 V; V_{O} or $V_{I} \le 4.5$ V	-	±5.0	±100	_	±100	μA
I _{PU/PD}	Power-up/down 3-State output current ⁴	$V_{CC} = 2.1 \text{ V}; V_O = 0.5 \text{ V}; V_I = \text{GND or } V_{CC};$ $V_{OE} = \text{Don't care}$	-	±5.0	±50	-	±50	μΑ
I _{OZH}	3-State output HIGH current	V_{CC} = 5.5 V; V_{O} = 2.7 V; V_{I} = V_{IL} or V_{IH}	-	1.0	10	-	10	μΑ
I _{OZL}	3-State output LOW current	V_{CC} = 5.5 V; V_{O} = 0.5 V; V_{I} = V_{IL} or V_{IH}	-	-1.0	-10	-	-10	μA
I _{CEX}	Output HIGH leakage current	V_{CC} = 5.5 V; V_{O} = 5.5 V; V_{I} = GND or V_{CC}	-	50	50	-	50	μΑ
Ι _Ο	Output current ¹	$V_{CC} = 5.5 \text{ V}; V_{O} = 2.5 \text{ V}$	-50	-80	-180	-50	-180	mA
I _{CCH}		V_{CC} = 5.5 V; Outputs HIGH; V _I = GND or V _{CC}	-	0.5	1	-	1	mA
I _{CCL}	Quiescent supply current	V_{CC} = 5.5V; Outputs LOW; V _I = GND or V _{CC}	-	9.0	19	-	19	mA
I _{CCZ}		V_{CC} = 5.5V; Outputs 3–State; V _I = GND or V _{CC}	-	0.5	1	-	1	mA
ΔI_{CC}	Additional supply current per input pin ²	V_{CC} = 5.5V; one input at 3.4 V, other inputs at V_{CC} or GND	-	0.2	1	-	1	mA

NOTES:

1. Not more than one output should be tested at a time, and the duration of the test should not exceed one second.

Not more than one output should be tested at a time, and the duration of the test should not exceed one second.
 This is the increase in supply current for each input at 3.4V.
 For valid test results, data must not be loaded into the flip-flops (or latches) after applying the power.
 This parameter is valid for any V_{CC} between 0V and 2.1V with a transition time of up to 10msec. From V_{CC} = 2.1V to V_{CC} = 5V ± 10% a transition time of up to 100µsec is permitted.

AC CHARACTERISTICS

GND = 0 V, t_{R} = t_{F} = 2.5 ns, C_{L} = 50 pF, R_{L} = 500 Ω

SYMBOL	PARAMETER	WAVEFORM	T _{amb} = +25 °C V _{CC} = + 5.0 V			T _{amb} = -40 ° V _{CC} = +5.0	UNIT	
			MIN	TYP	MAX	MIN	MAX	
f _{MAX}	Maximum clock frequency	1	140	190	-	140		MHz
t _{PLH} t _{PHL}	Propagation delay nCP to nQx	1	1.4 1.2	2.3 1.9	3.2 2.6	1.4 1.2	3.7 2.9	ns
t _{PHL}	Propagation delay nMR to nQx	2	2.0	3.3	4.3	2.0	5.0	ns
t _{PZH} t _{PZL}	Output enable time to HIGH and LOW level	4 5	1.3 1.2	2.4 2.1	3.2 2.9	1.3 1.2	3.9 3.4	ns
t _{PHZ} t _{PLZ}	Output disable time from HIGH and LOW level	4 5	1.7 1.6	2.9 2.3	4.0 3.2	1.7 1.6	4.7 3.4	ns

AC SET-UP REQUIREMENTS

GND = 0 V, t_R = t_F = 2.5 ns, C_L = 50 pF, R_L = 500 Ω

SYMBOL	PARAMETER	WAVEFORM	T _{amb} = V _{CC} =	+25 °C + 5.0 V	T _{amb} = −40 °C to +85 °C V _{CC} = +5.0 V ± 0.5V	UNIT
			MIN	TYP	MIN	
t _s (H) t _s (L)	Set-up time, HIGH or LOW nDx to nCP	3	2.0 1.5	1.3 0.9	2.0 1.5	ns
t _h (H) t _h (L)	Hold time, HIGH or LOW nDx to nCP	3	1.5 1.5	-0.9 -1.2	1.5 1.5	ns
t _w (H) t _w (L)	nCP pulse width HIGH or LOW	1	3.3 3.3	1.7 1.7	3.3 3.3	ns
t _s (H) t _s (L)	Set-up time, HIGH or LOW nCE to nCP	3	1.5 2.0	0.9 0.9	1.5 2.0	ns
t _h (H) t _h (L)	Hold time, HIGH or LOW nCE to nCP	3	1.5 1.5	-0.8 -0.9	1.5 1.5	ns
t _w (L)	nMR pulse width, LOW	2	3.0	1.7	3.0	ns
t _{rec}	Recovery time nMR to nCP	2	2.5	1.0	2.5	ns

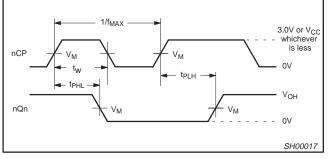
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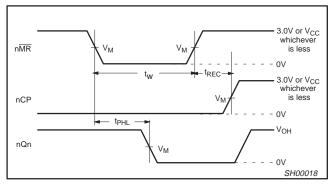
AC WAVEFORMS

For all waveforms, $V_M = 1.5$ V.

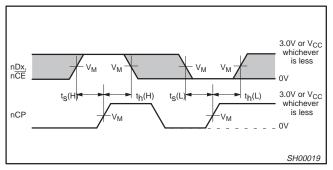
The shaded areas indicate when the input is permitted to change for predictable output performance.



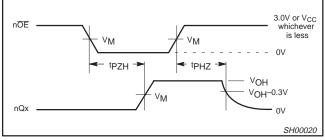
Waveform 1. Propagation Delay, Clock Input to Output, Clock Pulse Width, and Maximum Clock Frequency



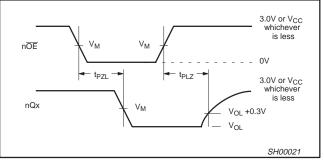
Waveform 2. Master Reset Pulse Width, Master Reset to Output Delay and Master Reset to Clock Recovery Time



Waveform 3. Data Set-up and Hold Times



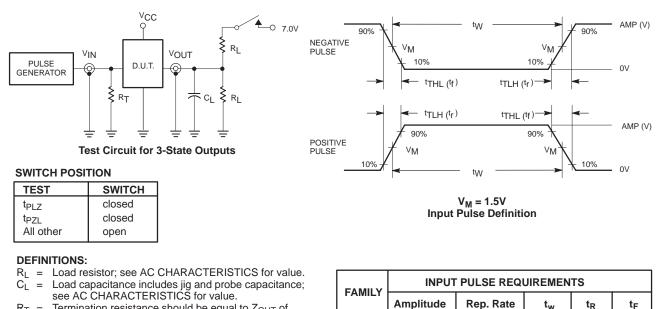
Waveform 4. 3-State Output Enable Time to HIGH Level and Output Disable Time from HIGH Level



Waveform 5. 3-State Output Enable Time to LOW Level and Output Disable Time from LOW Level

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TEST CIRCUIT AND WAVEFORM

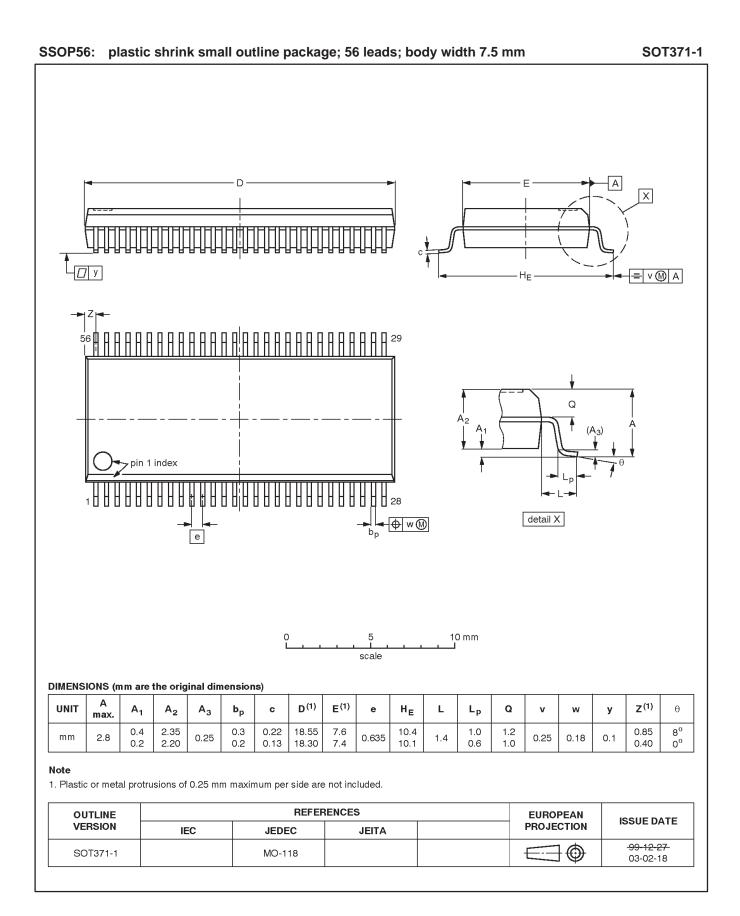


 $R_T =$ Termination resistance should be equal to ZOUT of pulse generators.

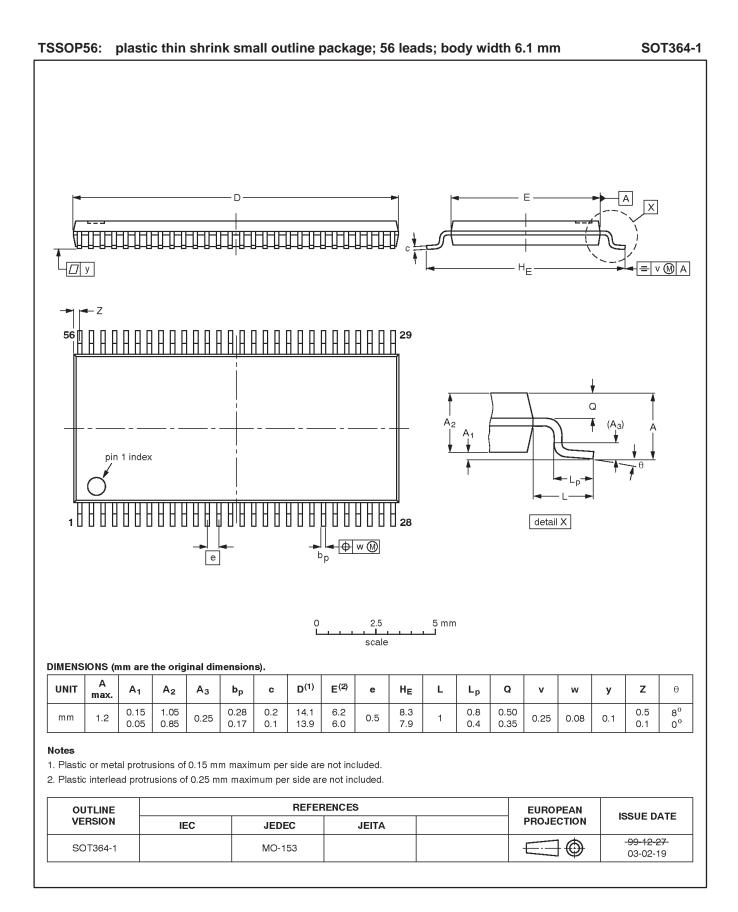
FAMILY	INPUT PULSE REQUIREMENTS							
	Amplitude	Rep. Rate	t _w	t _R	t _F			
74ABT16	3.0V	1MHz	500ns	2.5ns	2.5ns			

SH00022

74ABT16823A



74ABT16823A



74ABT16823A

REVISION HISTORY

Rev	Date	Description		
_3	20040202	Product data (9397 750 12833); 853-1791 ECN 01-A15432 of 27 January 2004. Replaces data sheet 74ABT_H16823A_2 of 1998 February 27 (9397 750 03502).		
		Modifications:		
		 Delete all references to 74ABTH16823A (product discontinued). 		
_2	19980227	Product specification (9397 750 03502); ECN 853-1791 19025 of 27 February 1998. Supersedes data of 1995 Sep 28.		

Data sheet status

Level	Data sheet status ^[1]	Product status ^{[2] [3]}	Definitions
I	Objective data	Development	This data sheet contains data from the objective specification for product development. Philips Semiconductors reserves the right to change the specification in any manner without notice.
II	Preliminary data	Qualification	This data sheet contains data from the preliminary specification. Supplementary data will be published at a later date. Philips Semiconductors reserves the right to change the specification without notice, in order to improve the design and supply the best possible product.
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Limiting values definition — Limiting values given are in accordance with the Absolute Maximum Rating System (IEC 60134). Stress above one or more of the limiting values may cause permanent damage to the device. These are stress ratings only and operation of the device at these or at any other conditions above those given in the Characteristics sections of the specification is not implied. Exposure to limiting values for extended periods may affect device reliability.

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